

Search Notes

Application/Control No.

10/066,060

Examiner

Phallaka Kik

Applicant(s)/Patent under
Reexamination

TEIG ET AL.

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	13,14,9,10 .4	10/19/2004	PK
Above	updated	5/31/2005	PK
Above	updated	12/7/2005	PK
Above	new	12/7/2005	PK
Above	new	4/4/2006	PK
Above	updated	4/4/2006	PK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
716	13,14,9	4/4/2006	PK
716	10,4	4/4/2006	PK
--USPGPUB (see attached)		4/4/2006	PK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS (EAST) --USPAT, USPGPUB Class/Sub searched: 716/1-18 (see attached)	10/19/2004	PK
--EPO, JPO, IBM TDB, Derwent (see attached)	10/19/2004	PK
IEEE/IEEE Xplore (see attached)	10/19/2004	PK
Above updated search	5/31/2005	PK
Above updated and new search (see attached)	12/7/2005	PK
Above updated and new search (see attached)	4/4/2006	PK